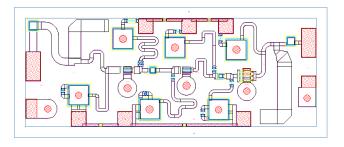


## Ka Band Wideband LNA/Driver

### **TGA1319C**



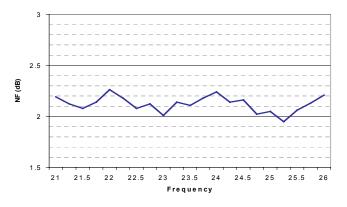
Chip Dimensions 2.169 mm x .904 mm

## **Key Features and Performance**

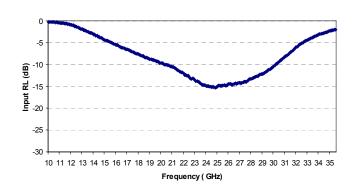
- 0.15um pHEMT Technology
- 16-30 GHz Frequency Range
- 2.25 dB Nominal Noise Figure midband
- 21 dB Nominal Gain
- 14 dBm Pout
- 5V, 60 mA

### **Primary Applications**

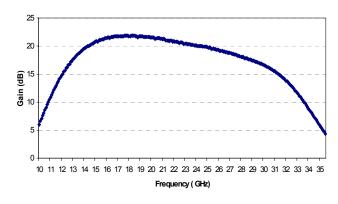
- Point-to-Point Radio
- Point-to-Multipoint Communications



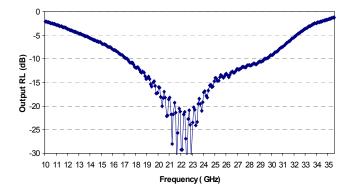
Typical NF @ 25C



Typical S11 @ 25C



Typical Gain @ 25C



Typical S22 @ 25C

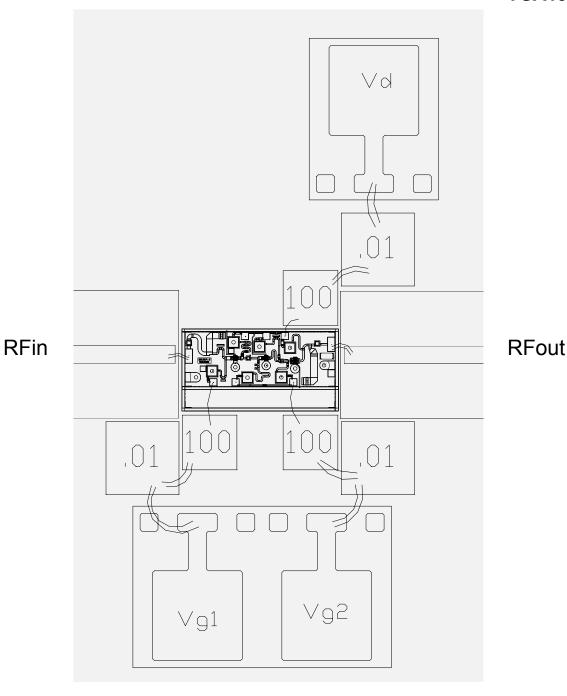
Note: Devices designated as EPU are typically early in their characterization process prior to finalizing all electrical and process specifications. Specifications subject to change without notice



## **Advance Product Information**

August 29, 2000

### **TGA1319C**



TGA1319C- Recommended Assembly Drawing

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# Advance Product Information August 29, 2000

**TGA1319C** 

### **Assembly Process Notes**

### Reflow process assembly notes:

- AuSn (80/20) solder with limited exposure to temperatures at or above 300°C
- alloy station or conveyor furnace with reducing atmosphere
- no fluxes should be utilized
- coefficient of thermal expansion matching is critical for long-term reliability
- storage in dry nitrogen atmosphere

### Component placement and adhesive attachment assembly notes:

- vacuum pencils and/or vacuum collets preferred method of pick up
- avoidance of air bridges during placement
- force impact critical during auto placement
- organic attachment can be used in low-power applications
- curing should be done in a convection oven; proper exhaust is a safety concern
- microwave or radiant curing should not be used because of differential heating
- coefficient of thermal expansion matching is critical

### Interconnect process assembly notes:

- thermosonic ball bonding is the preferred interconnect technique
- force, time, and ultrasonics are critical parameters
- aluminum wire should not be used
- discrete FET devices with small pad sizes should be bonded with 0.0007-inch wire
- maximum stage temperature: 200 ° C

GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.

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Datasheets for electronics components.